

BUL128

HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- STMicroelectronics PREFERRED SALESTYPE
- NPN TRANSISTOR
- HIGH VOLTAGE CAPABILITY
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED

APPLICATIONS:

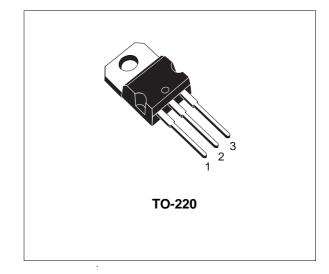
 ELECTRONIC BALLASTS FOR FLUORESCENT LIGHTING

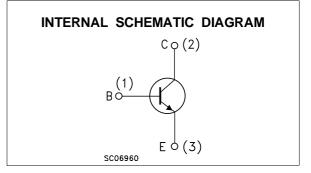
DESCRIPTION

The device is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and medium voltage capability.

It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining the wide RBSOA.

The device is designed for use in lighting applications and low cost switch-mode power supplies.





ABSOLUTE MAXIMUM RATINGS

| Symbol | Parameter | Value | Unit |
|------------------|---|------------|------|
| V _{CES} | Collector-Emitter Voltage (V _{BE} = 0) | 700 | V |
| Vceo | Collector-Emitter Voltage $(I_B = 0)$ | 400 | V |
| V _{EBO} | Emitter-Base Voltage ($I_C = 0$) | 9 | V |
| lc | Collector Current | 4 | А |
| I _{CM} | Collector Peak Current (t _p < 5 ms) | 8 | А |
| Ι _Β | Base Current | 2 | А |
| I _{BM} | Base Peak Current (t _p < 5 ms) | 4 | А |
| P _{tot} | Total Dissipation at $T_c = 25$ °C | 70 | W |
| T _{stg} | Storage Temperature | -65 to 150 | °C |
| Tj | Max. Operating Junction Temperature | 150 | °C |

November 2001

THERMAL DATA

| R _{thj-case} | Thermal Resistance Junction-Case | Max | 1.78 | °C/W |
|-----------------------|-------------------------------------|-----|------|------|
| R _{thj-amb} | Thermal Resistance Junction-Ambient | Max | 62.5 | °C/W |

ELECTRICAL CHARACTERISTICS ($T_{case} = 25 \, {}^{\circ}C$ unless otherwise specified)

| Symbol | Parameter Collector Cut-off Current (V _{BE} = -1.5 V) | Test Conditions | | Min. | Тур. | Max. | Unit |
|----------------------------------|--|---|--|----------------|------------|-------------------|------------------|
| ICES | | V _{CE} = 700 V V _{CE} = 700 V | T _j = 125 ^o C | | | 100 500 | μΑ μΑ |
| V _{EBO} | Emitter-Base Voltage (I _C = 0) | I _E = 10 mA | | 9 | | | V |
| $V_{CEO(sus)^*}$ | Collector-Emitter Sustaining Voltage (I _B = 0) | I _C = 100 mA | L = 25 mH | 400 | | | V |
| ICEO | Collector Cut-Off Current (I _B = 0) | V _{CE} = 400 V | | | | 250 | μA |
| V _{CE(sat)} * | Collector-Emitter Saturation Voltage | $I_{C} = 0.5 A$ $I_{C} = 1 A$ $I_{C} = 2.5 A$ $I_{C} = 4 A$ | $I_B = 0.1 A$ $I_B = 0.2 A$ $I_B = 0.5 A$ $I_B = 1 A$ | | 0.5 | 0.7 1 1.5 | V V V V |
| V _{BE(sat)} * | Base-Emitter Saturation Voltage | $I_{C} = 0.5 \text{ A}$ $I_{C} = 1 \text{ A}$ $I_{C} = 2.5 \text{ A}$ | $I_{B} = 0.1 A$ $I_{B} = 0.2 A$ $I_{B} = 0.5 A$ | | | 1.1 1.2 1.3 | V V V |
| h _{FE} * | DC Current Gain | $I_C = 10 \text{ mA}$ $I_C = 2 \text{ A}$ Group A Group B | V _{CE} = 5 V V _{CE} = 5 V | 10 14 25 | | 28 40 | |
| t _s t _f | RESISTIVE LOAD Storage Time Fall Time | $V_{CC} = 125 V$ $I_{B1} = 0.4 A$ $T_p = 30 \mu s$ | $I_{C} = 2 A$ $I_{B2} = -0.4 A$ (see fig.2) | 1.5 | 0.2 | 3 0.4 | μs μs |
| t _s t _f | INDUCTIVE LOAD Storage Time Fall Time | $I_{C} = 2 A$ $V_{BE(off)} = -5 V$ $V_{clamp} = 200 V$ | $I_{B1} = 0.4 \text{ A}$ $R_{BB} = 0 \Omega$ (see fig.1) | | 0.6 0.1 | 1 0.2 | μs μs |

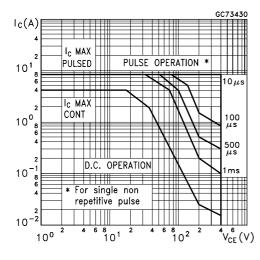
* Pulsed: Pulse duration = $300 \,\mu$ s, duty cycle 1.5 %

Note : Product is pre-selected in DC current gain (GROUP A and GROUP B). STMicroelectronics reserves the right to ship either groups according to production availability. Please contact your nearest STMicroelectronics sales office for delivery details.

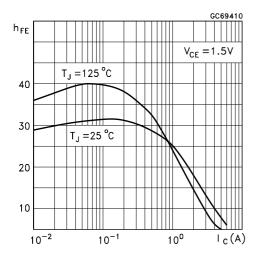
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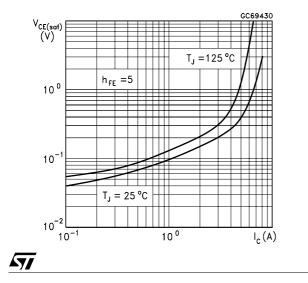
Safe Operating Areas



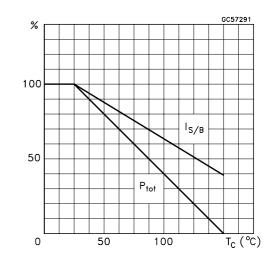
DC Current Gain



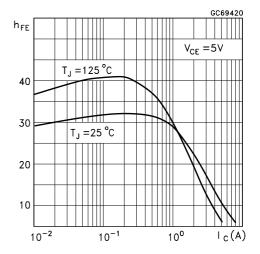
Collector Emitter Saturation Voltage



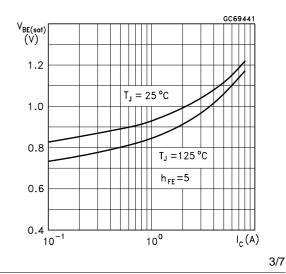
Derating Curve



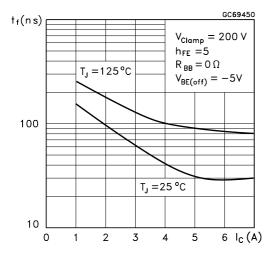
DC Current Gain



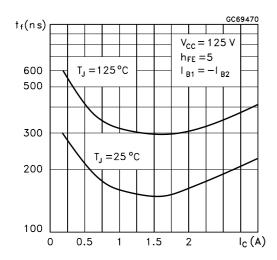




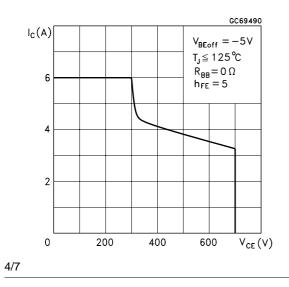
Inductive Load Fall Time



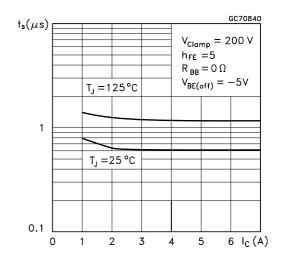
Resistive Load Fall Time

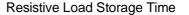


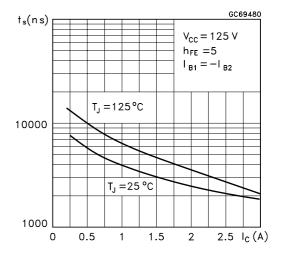
Reverse Biased SOA



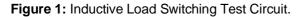
Inductive Load Storage Time







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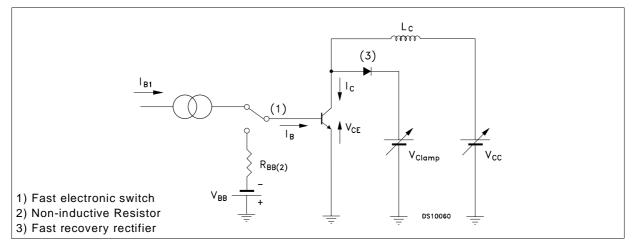
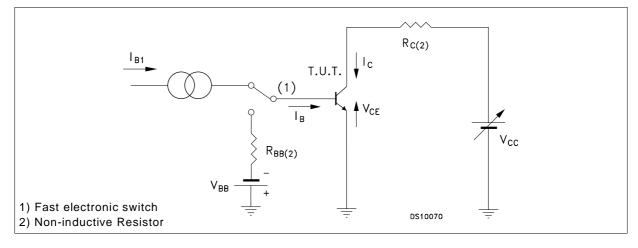


Figure 2: Resistive Load Switching Test Circuit.



С 1.23 1.32 0.048 2.72 D 2.40 0.094 Е 0.49 0.70 0.019 F 0.61 0.88 0.024 F1 1.14 1.70 0.044 F2 1.14 1.70 0.044 G 4.95 5.15 0.194 G1 2.40 2.70 0.094 H2 10.00 10.40 0.394 L2 16.40 0.645 L4 13.00 14.00 0.511 L5 2.65 2.95 0.104 L6 15.25 15.75 0.600 L7 6.20 6.60 0.244 L9 3.50 3.93 0.137 Μ 2.60 0.102

mm

TYP.



MAX.

4.60

inch

TYP.

MAX.

0.181

0.052

0.107

0.027

0.034

0.067

0.067

0.202

0.106

0.409

0.551

0.116

0.620

0.260

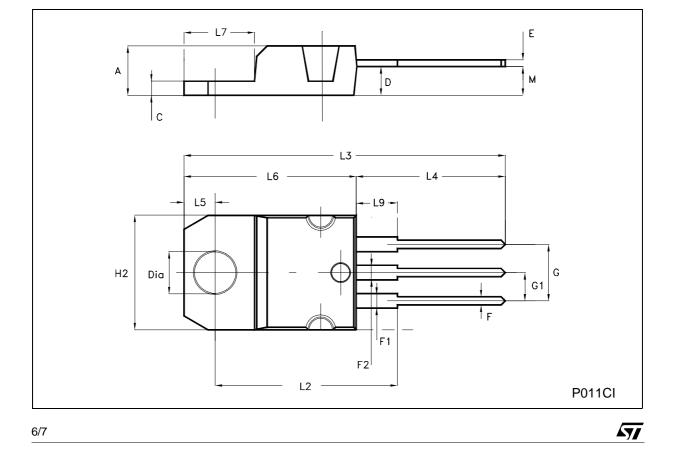
0.154

0.151

MIN.

0.173

0.147



3.85

MIN.

4.40

3.75

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DIM.

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